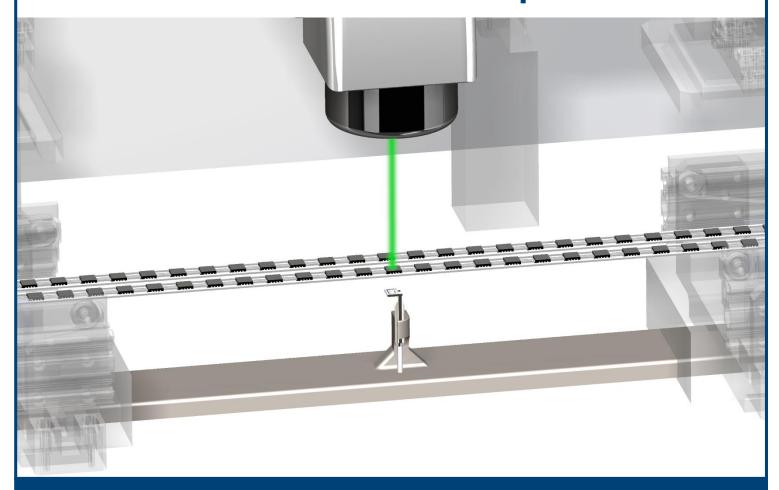
High-speed non-contact Ultrasonic Inline Inspection



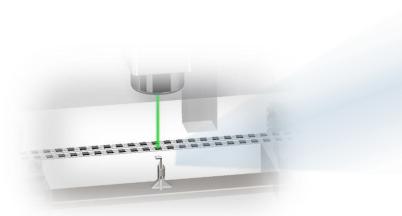


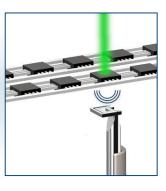
Functionality

XARION's laser-based technology enables the ultrasonic inspection of semiconductor components without any coupling liquid. A single laser pulse generates an acoustic fingerprint of each sample revealing internal delaminations and defects with a throughput of up to 1000 samples per second. The fully non-contact sensor technology can be easily integrated into a high-volume production line, saving costs for offline analysis, and ensuring inspection of 100% of the components, e.g. packaged devices for the automotive sector.

Features

- 100% documented safety for your customer
- Unique non-contact single-shot ultrasound technology
- Fully automated inline inspection of up to 1000 samples per second
- Easy integration into high-throughput production environment:
 - No water coupling, and no drying of samples necessary
 - No interference with other production steps
- Combination with offline non-contact imaging of defective components for further analysis possible





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